



Welcome to **E-XFL.COM** 

## Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	684
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	104
Number of Gates	4000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	132-BCPGA
Supplier Device Package	132-CPGA (34.54x34.54)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/5962-9322101mxa

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



# 1 - ACT 2 Family Overview

### **General Description**

The ACT 2 family represents Actel's second generation of field programmable gate arrays (FPGAs). The ACT 2 family presents a two-module architecture, consisting of C-modules and S-modules. These modules are optimized for both combinatorial and sequential designs. Based on Actel's patented channeled array architecture, the ACT 2 family provides significant enhancements to gate density and performance while maintaining downward compatibility with the ACT 1 design environment and upward compatibility with the ACT 3 design environment. The devices are implemented in silicon gate, 1.0-μm, two-level metal CMOS, and employ Actel's PLICE® antifuse technology. This revolutionary architecture offers gate array design flexibility, high performance, and fast time-to-production with user programming. The ACT 2 family is supported by the Designer and Designer Advantage Systems, which offers automatic pin assignment, validation of electrical and design rules, automatic placement and routing, timing analysis, user programming, and diagnostic probe capabilities. The systems are supported on the following platforms: 386/486™ PC, Sun™, and HP™ workstations. The systems provide CAE interfaces to the following design environments: Cadence, Viewlogic®, Mentor Graphics®, and OrCAD™.



To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. EQ 4 shows a piece-wise linear summation over all components.

Power =VCC<sup>2</sup> \* [(m \* 
$$C_{EQM}$$
 \*  $f_{m}$ )<sub>modules</sub> + (n \*  $C_{EQI}$  \*  $f_{n}$ ) <sub>inputs</sub> + (p \* ( $C_{EQO}$ +  $C_{L}$ ) \*  $f_{D}$ )outputs + 0.5 \* (q1 \*  $C_{EQCR}$  \*  $f_{q1}$ )<sub>routed\_Cik1</sub> + (r1 \*  $f_{q1}$ )<sub>routed\_Cik1</sub> + 0.5 \* (q2 \*  $C_{EQCR}$  \*  $f_{q2}$ )<sub>routed\_Cik2</sub> + ( $r_{2}$  \*  $f_{q2}$ )<sub>routed\_Cik2</sub>

EQ 4

#### Where:

m = Number of logic modules switching at f<sub>m</sub>

n = Number of input buffers switching at f<sub>n</sub>

p = Number of output buffers switching at f<sub>n</sub>

q1 = Number of clock loads on the first routed array clock

q2 = Number of clock loads on the second routed array clock

r<sub>1</sub> = Fixed capacitance due to first routed array clock

r<sub>2</sub> = Fixed capacitance due to second routed array clock

C<sub>FOM</sub> = Equivalent capacitance of logic modules in pF

C<sub>EOI</sub> = Equivalent capacitance of input buffers in pF

C<sub>EQO</sub> = Equivalent capacitance of output buffers in pF

C<sub>EOCR</sub> = Equivalent capacitance of routed array clock in pF

C<sub>I</sub> = Output lead capacitance in pF

f<sub>m</sub> = Average logic module switching rate in MHz

f<sub>n</sub> = Average input buffer switching rate in MHz

f<sub>p</sub> = Average output buffer switching rate in MHz

f<sub>q1</sub> = Average first routed array clock rate in MHz

f<sub>g2</sub> = Average second routed array clock rate in MHz

Table 2-7 • Fixed Capacitance Values for Microsemi FPGAs

Device Type	r1, routed_Clk1	r2, routed_Clk2
A1225A	106	106.0
A1240A	134	134.2
A1280A	168	167.8



### **Determining Average Switching Frequency**

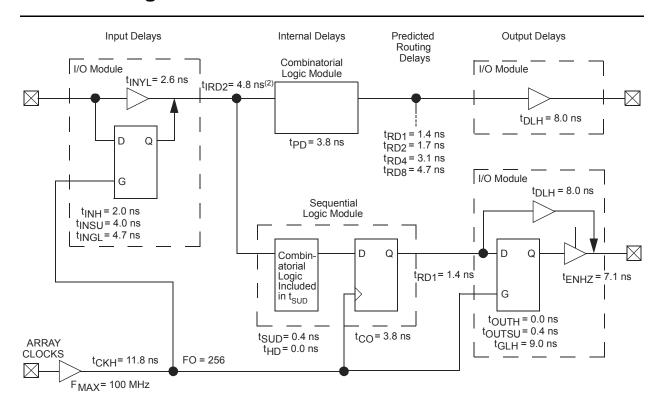
To determine the switching frequency for a design, you must have a detailed understanding of the data input values to the circuit. The following guidelines are meant to represent worst-case scenarios so that they can be generally used to predict the upper limits of power dissipation. These guidelines are given in Table 2-8.

Table 2-8 • Guidelines for Predicting Power Dissipation

Data	Value
Logic Modules (m)	80% of modules
Inputs switching (n)	# inputs/4
Outputs switching (p)	# output/4
First routed array clock loads (q1)	40% of sequential modules
Second routed array clock loads (q2)	40% of sequential modules
Load capacitance (C <sub>L</sub> )	35 pF
Average logic module switching rate (f <sub>m</sub> )	F/10
Average input switching rate (f <sub>n</sub> )	F/5
Average output switching rate (f <sub>p</sub> )	F/10
Average first routed array clock rate (f <sub>q1</sub> )	F
Average second routed array clock rate (f <sub>q2</sub> )	F/2

2-6 Revision 8

# **ACT 2 Timing Model<sup>1</sup>**



#### Notes:

- 1. Values shown for A1240A-2 at worst-case commercial conditions.
- 2. Input module predicted routing delay

Figure 2-1 • Timing Model



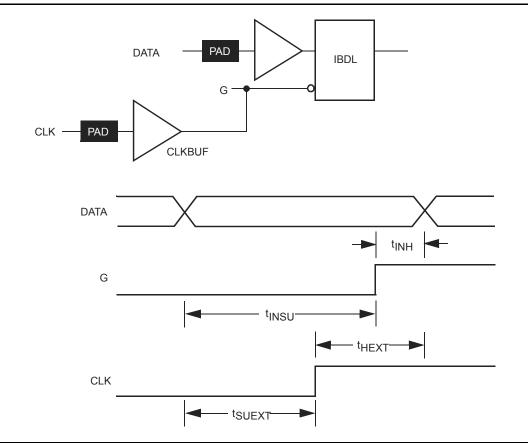


Figure 2-7 • Input Buffer Latches

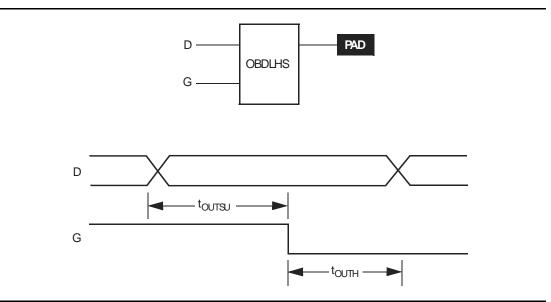


Figure 2-8 • Output Buffer Latches

2-10 Revision 8



### **Timing Derating Factor (Temperature and Voltage)**

Table 2-9 • Timing Derating Factor (Temperature and Voltage)

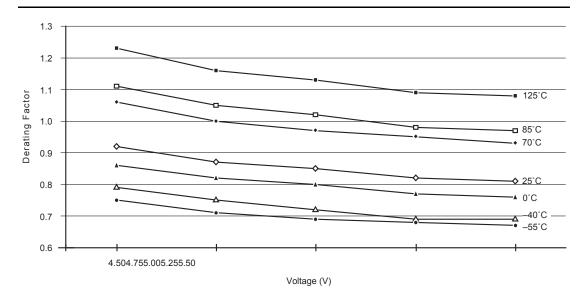
(Commercial Minimum/Maximum Specification) x	Indus	Industrial Militar		tary
	Min.	Max.	Min.	Max.
	0.69	1.11	0.67	1.23

Table 2-10 • Timing Derating Factor for Designs at Typical Temperature ( $T_J = 25^{\circ}C$ ) and Voltage (5.0 V)

(Commercial Maximum Specification) x	0.85
--------------------------------------	------

Table 2-11 • Temperature and Voltage Derating Factors (normalized to Worst-Case Commercial, TJ = 4.75 V, 70°C)

	<b>-55</b>	-40	0	25	70	85	125
4.50	0.75	0.79	0.86	0.92	1.06	1.11	1.23
4.75	0.71	0.75	0.82	0.87	1.00	1.05	1.13
5.00	0.69	0.72	0.80	0.85	0.97	1.02	1.13
5.25	0.68	0.69	0.77	0.82	0.95	0.98	1.09
5.50	0.67	0.69	0.76	0.81	0.93	0.97	1.08



Note: This derating factor applies to all routing and propagation delays.

Figure 2-9 • Junction Temperature and Voltage Derating Curves (normalized to Worst-Case Commercial, T<sub>J</sub> = 4.75 V, 70°C)



**Detailed Specifications** 

### A1240A Timing Characteristics (continued)

Table 2-16 • A1240A Worst-Case Commercial Conditions, VCC = 4.75 V,  $T_J$  = 70°C

I/O Mod	I/O Module Input Propagation Delays			peed	–1 S	peed	Std. Speed		Units
Paramet	ter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>INYH</sub>	Pad to Y High			2.9		3.3		3.8	ns
t <sub>INYL</sub>	Pad to Y Low			2.6		3.0		3.5	ns
t <sub>INGH</sub>	G to Y High			5.0		5.7		6.6	ns
t <sub>INGL</sub>	G to Y Low			4.7		5.4		6.3	ns
Input Mo	odule Predicted Input Routing Del	ays <sup>*</sup>		.1.					
t <sub>IRD1</sub>	FO = 1 Routing Delay			4.2		4.8		5.6	ns
t <sub>IRD2</sub>	FO = 2 Routing Delay			4.8		5.4		6.4	ns
t <sub>IRD3</sub>	FO = 3 Routing Delay			5.4		6.1		7.2	ns
t <sub>IRD4</sub>	FO = 4 Routing Delay			5.9		6.7		7.9	ns
t <sub>IRD8</sub>	FO = 8 Routing Delay			7.9		8.9		10.5	ns
Global (	Clock Network		•	•		•		•	•
t <sub>CKH</sub>	Input Low to High	FO = 32		10.2		11.0		12.8	ns
	FO = 256		11.8		13.0		15.7		
t <sub>CKL</sub>	Input High to Low	FO = 32		10.2		11.0		12.8	ns
		FO = 256		12.0		13.2		15.9	
t <sub>PWH</sub>	Minimum Pulse Width High	FO = 32	3.8		4.5		5.5		ns
		FO = 256	4.1		5.0		5.8		
t <sub>PWL</sub>	Minimum Pulse Width Low	FO = 32	3.8		4.5		5.5		ns
		FO = 256	4.1		5.0		5.8		
t <sub>CKSW</sub>	Maximum Skew	FO = 32		0.5		0.5		0.5	ns
		FO = 256		2.5		2.5		2.5	
t <sub>SUEXT</sub>	Input Latch External Setup	FO = 32	0.0		0.0		0.0		ns
		FO = 256	0.0		0.0		0.0		
t <sub>HEXT</sub>	Input Latch External Hold	FO = 32	7.0		7.0		7.0		ns
		FO = 256	11.2		11.2		11.2		1
t <sub>P</sub>	Minimum Period	FO = 32	8.1		9.1		11.1		ns
		FO = 256	8.8		10.0		11.7		1
f <sub>MAX</sub>	Maximum Frequency	FO = 32		125.0		110.0		90.0	ns
		FO = 256		115.0		100.0		85.0	1

Note: \*These parameters should be used for estimating device performance. Optimization techniques may further reduce delays by 0 to 4 ns. Routing delays are for typical designs across worst-case operating conditions. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

2-16 Revision 8



### A1240A Timing Characteristics (continued)

Table 2-17 • A1240A Worst-Case Commercial Conditions, VCC = 4.75 V,  $T_J$  = 70°C

TTL Output Module Timing <sup>1</sup>		-2 S	peed	–1 S	peed Std. Speed		Units	
Parame	Parameter/Description		Max.	Min.	Max.	Min.	Max.	
t <sub>DLH</sub>	Data to Pad High		8.0		9.0		10.6	ns
t <sub>DHL</sub>	Data to Pad Low		10.1		11.4		13.4	ns
t <sub>ENZH</sub>	Enable Pad Z to High		8.9		10.0		11.8	ns
t <sub>ENZL</sub>	Enable Pad Z to Low		11.7		13.2		15.5	ns
t <sub>ENHZ</sub>	Enable Pad High to Z		7.1		8.0		9.4	ns
t <sub>ENLZ</sub>	Enable Pad Low to Z		8.4		9.5		11.1	ns
t <sub>GLH</sub>	G to Pad High		9.0		10.2		11.9	ns
t <sub>GHL</sub>	G to Pad Low		11.2		12.7		14.9	ns
$d_{TLH}$	Delta Low to High		0.07		0.08		0.09	ns/pF
$d_THL$	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS	Output Module Timing <sup>1</sup>							
t <sub>DLH</sub>	Data to Pad High		10.2		11.5		13.5	ns
t <sub>DHL</sub>	Data to Pad Low		8.4		9.6		11.2	ns
t <sub>ENZH</sub>	Enable Pad Z to High		8.9		10.0		11.8	ns
t <sub>ENZL</sub>	Enable Pad Z to Low		11.7		13.2		15.5	ns
t <sub>ENHZ</sub>	Enable Pad High to Z		7.1		8.0		9.4	ns
t <sub>ENLZ</sub>	Enable Pad Low to Z		8.4		9.5		11.1	ns
t <sub>GLH</sub>	G to Pad High		9.0		10.2		11.9	ns
t <sub>GHL</sub>	G to Pad Low		11.2		12.7		14.9	ns
$d_{TLH}$	Delta Low to High		0.12		0.13		0.16	ns/pF
d <sub>THL</sub>	Delta High to Low		0.09		0.10		0.12	ns/pF

#### Notes:

- 1. Delays based on 50 pF loading.
- 2. SSO information can be found at www.microsemi.com/soc/techdocs/appnotes/board\_consideration.aspx.



### **Pin Descriptions**

#### CLKA Clock A (Input)

TTL Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

#### CLKB Clock B (Input)

TTL Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

#### DCLK Diagnostic Clock (Input)

TTL Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

#### GND Ground

Low supply voltage.

#### I/O Input/Output (Input, Output)

The I/O pin functions as an input, output, three-state, or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/O pins are automatically driven Low by the ALS software.

#### MODE Mode (Input)

The MODE pin controls the use of multifunction pins (DCLK, PRA, PRB, SDI). When the MODE pin is High, the special functions are active. When the MODE pin is Low, the pins function as I/Os. To provide Actionprobe capability, the MODE pin should be terminated to GND through a 10K resistor so that the MODE pin can be pulled High when required.

#### NC No Connection

This pin is not connected to circuitry within the device.

#### PRA Probe A (Output)

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

#### PRB Probe B (Output)

The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

#### SDI Serial Data Input (Input)

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

#### SDO Serial Data Output (Output)

Serial data output for diagnostic probe. SDO is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

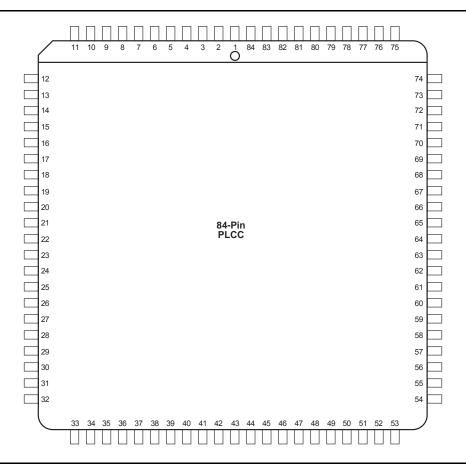
#### VCC 5.0 V Supply Voltage

High supply voltage.



# 3 – Package Pin Assignments

### **PL84**



#### Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx.



#### Package Pin Assignments

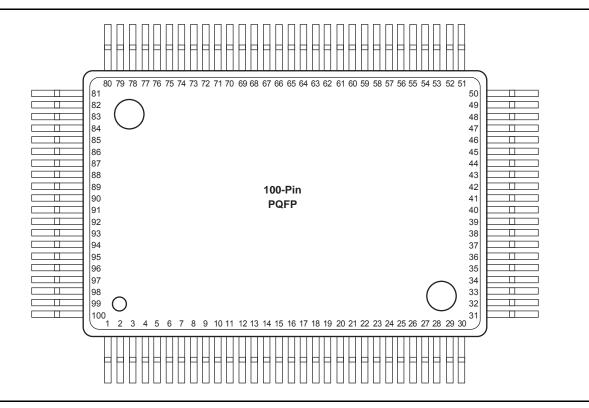
PL84				
Pin Number	A1225A Function	A1240A Function	A1280A Function	
2	CLKB, I/O	CLKB, I/O	CLKB, I/O	
4	PRB, I/O	PRB, I/O	PRB, I/O	
6	GND	GND	GND	
10	DCLK, I/O	DCLK, I/O	DCLK, I/O	
12	MODE	MODE	MODE	
22	VCC	VCC	VCC	
23	VCC	VCC	VCC	
28	GND	GND	GND	
43	VCC	VCC	VCC	
49	GND	GND	GND	
52	SDO	SDO	SDO	
63	GND	GND	GND	
64	VCC	VCC	VCC	
65	VCC	VCC	VCC	
70	GND	GND	GND	
76	SDI, I/O	SDI, I/O	SDI, I/O	
81	PRA, I/O	PRA, I/O	PRA, I/O	
83	CLKA, I/O	CLKA, I/O	CLKA, I/O	
84	VCC	VCC	VCC	

#### Notes:

- 1. All unlisted pin numbers are user I/Os.
- 2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

3-2 Revision 8

### **PQ100**



#### Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx



#### Package Pin Assignments

PQ100			
Pin Number	A1225A Function		
2	DCLK, I/O		
4	MODE		
9	GND		
16	VCC		
17	VCC		
22	GND		
34	GND		
40	VCC		
46	GND		
52	SDO		
57	GND		
64	GND		

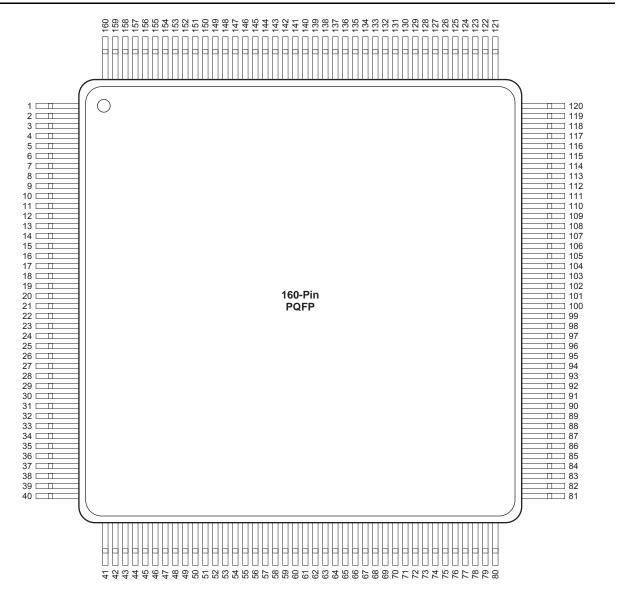
PQ100			
Pin Number	A1225A Function		
65	VCC		
66	VCC		
67	VCC		
72	GND		
79	SDI, I/O		
84	GND		
87	PRA, I/O		
89	CLKA, I/O		
90	VCC		
92	CLKB, I/O		
94	PRB, I/O		
96	GND		

#### Notes:

- 1. All unlisted pin numbers are user I/Os.
- 2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

3-4 Revision 8

### **PQ160**

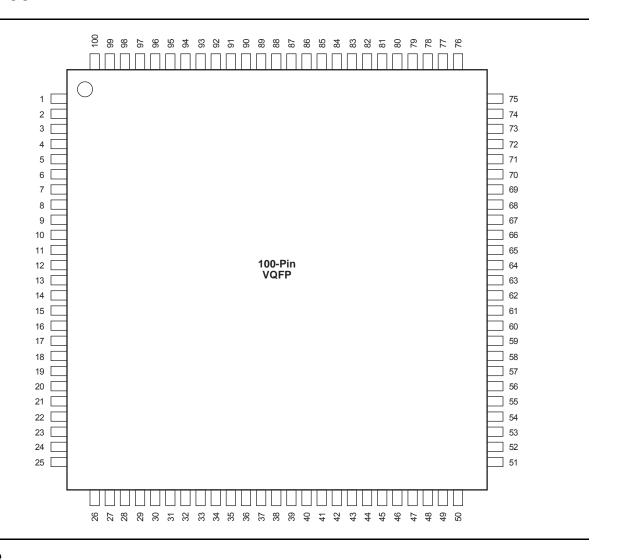


Note: This is the top view of the package

#### Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

### **VQ100**



#### Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx



#### Package Pin Assignments

VQ100				
Pin Number	A1225A Function			
2	MODE			
7	GND			
14	VCC			
15	VCC			
20	GND			
32	GND			
38	VCC			
44	GND			
50	SDO			
55	GND			
62	GND			
63	VCC			

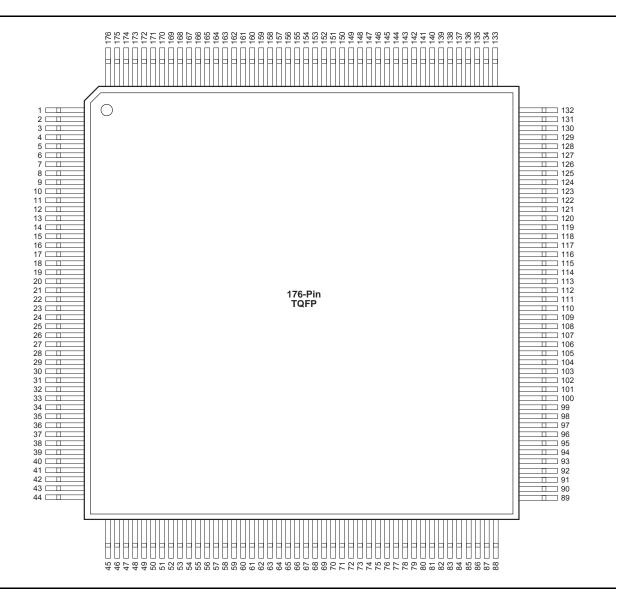
VQ100				
Pin Number	A1225A Function			
64	VCC			
65	VCC			
70	GND			
77	SDI, I/O			
82	GND			
85	PRA, I/O			
87	CLKA, I/O			
88	VCC			
90	CLKB, I/O			
92	PRB, I/O			
94	GND			
100	DCLK, I/O			

#### Notes:

- 1. All unlisted pin numbers are user I/Os.
- 2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

3-10 Revision 8

### **TQ176**



#### Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx



# 4 - Datasheet Information

## **List of Changes**

The following table lists critical changes that were made in each version of the datasheet.

Revision	Changes	Page		
Revision 8 (January 2012)				
	Package names used in Table 1 • ACT 2 Product Family Profile and throughout the document were revised to match standards given in <i>Package Mechanical Drawings</i> (SAR 27395).			
	The description for SDO pins had earlier been removed from the datasheet and has now been included again, in the "Pin Descriptions" section (SAR 35819).			
	SDO pin numbers had earlier been removed from package pin assignment tables in the datasheet, and have now been restored to the pin tables (SAR 35819).	3-2		
Revision 7 (June 2006)	The "Ordering Information" section was revised to include RoHS information.	II		
Revision 6 (December 2000)	In the "PG176" package, pin A3 was incorrectly assigned as CLKA, I/O. A3 is a user I/O. Pin A9 is CLKA, I/O.	3-21		